Serial No. 10/015,369 Page 2 of 4

<u>REMARKS</u>

Claims 1-11 are pending in the application.

The Examiner maintained, in the Advisory Action, that the claims cannot read on Fig. 2 because its corresponding description could only be found in the background section of the specification. Applicants point out, again, to the Examiner that the description in the specification only refers to Fig. 2 as an "assumed configuration" to illustrate improvements and problems identified by Applicants and solved by the claimed invention. Even the language highlighted by the Examiner, "it is difficult to connect in common phase the outputs of the two amplifiers 1 and 2 shown in Fig. 2 in the coupling unit 5," merely describes a difficulty recognized by Applicants themselves. Nowhere in this language is there any concession that any feature discussed or illustrated is prior art work of another.

The Examiner stated in the Advisory Action that "the improvement(s) do not start until figure 3...figure 4...[etc.]." Applicants respectfully point out that such figures merely illustrate exemplary embodiments of the invention. And as stated before, Fig. 2 merely illustrates an assumed configuration that illustrates the problems and improvements identified by the Applicants. Most importantly, Applicants have not conceded that the features illustrated in Fig. 2 reflect any techniques known or used by others prior to the Applicants' claimed invention. As such, Applicants respectfully submit that the claimed invention may encompass exemplary embodiments described in the specification so long as it is distinguishable from the prior art.

Applicants, once again, refer the Examiner to MPEP § 608.01(c), which states that the Background section of an application may include "the <u>problems</u> involved in the prior art <u>or other information</u> disclosed which are solved by the applicant's invention..." (Emphasis added)

84200677_1.DOC

Serial No. 10/015,369

Page 3 of 4

The recognition and description of such problems and "other information," which is "known to the applicant," included for illustrating problems solved by the claimed invention are not, themselves, admitted as prior art. And MPEP § 608.01(c) clearly provides for the inclusion of such "other information" distinct from admitted "prior art." Applicants also refer to MPEP § 2129, which requires an applicant's explicit statement identifying the work of another as "prior art." for all admissions of prior art. Indeed, MPEP § 2129 further states,

"even if labeled as 'prior art,' the work of the same inventive entity may not be considered prior art against the claims unless it falls under one of the statutory categories." (Emphasis in original)

Again, Applicants merely illustrate their own work in Fig. 2 on possible ways to improve existing techniques, and therefore, have not admitted such portions of the application as prior art work of another. Accordingly, Applicants, again, respectfully request that the Examiner withdraw the objection to Fig. 2.

Applicants refer to the February 13, 2007 Response to Office Action for remarks addressing the remaining issues in the final Office Action dated October 18, 2006.

In view of the remarks set forth above, this application is in condition for allowance which action is respectfully requested. However, if for any reason the Examiner should consider this application not to be in condition for allowance, the Examiner is respectfully requested to telephone the undersigned attorney at the number listed below prior to issuing a further Action.

84200677_1.DOC

Serial No. 10/015,369 Page 4 of 4

Any fee due with this paper may be charged to Deposit Account No. 50-1290.

Respectfully submitted,

Dexter T. Chang Reg. No. 44,071

CUSTOMER NUMBER 026304 Telephone: (212) 940-6384 Fax: (212) 940-8986 or 8987

Docket No.: 100794-00105 (FUJH 19.249)

DTC:bf

84200677_1.DOC

3 Simulated measurements

To illustrate the applicability of the method we have performed computer simulations of homodyne measurements and used the kernels $K_k(x,\vartheta)$ to determine the moments Ψ_k . For comparison, we have also simulated double homodyne measurements to get exponential phase moments that correspond to the radially integrated Q function. In the computer simulations the state to be detected is the phase squeezed state $|\alpha, s\rangle$ with the coherent amplitude $\alpha = 5 \times e^{i\varphi_0}$, $\varphi_0 = 0.6$, and the squeeze parameter s = 6 (the mean photon number of this state is $\langle n \rangle = 26.04$). For both the homodyne and the double homodyne measurements the total number of measurement events is $N_e = 6020$. For the homodyne measurements the LO phase ϑ takes 41 values equidistantly distributed over the 2π interval. As shown in [8], the statistical error of the sampled phase moments depends on the numbers of measurement events for different ϑ . By a proper distribution of the total number N_e for individual phases ϑ we can decrease the statistical error of various moments Ψ_k . In order to minimize the statistical error of the first moment Ψ_1 , we increased the number of measurement events for such ϑ for which the peak of $p(x,\vartheta)$ is near x=0 (maximum 800 events), whereas for ϑ yielding a peak far from zero the number of events was small (minimum 10 events).

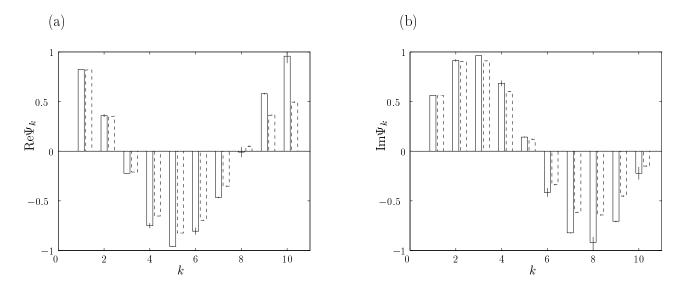


Figure 2: Real (a) and imaginary (b) parts of the experimentally determined exponential phase moments Ψ_k . Bars with full lines: direct sampling from balanced homodyning, bars with dashed lines: double homodyning. The vertical lines represent the estimated statistical error.

The experimentally determined phase moments together with the estimated statistical errors are shown in Fig. 2. We can see that the absolute values of moments of the integrated Q function are smaller than the corresponding values of the canonical distribution; the difference becomes larger with increasing k. This corresponds to the fact that the integrated Q function smears the structure of the canonical distribution.

Let us compare the statistical errors. For the odd moments the errors are approximately of the same magnitude in the two methods, whereas for the even moments the sampling method yields larger errors. This reflects the qualitatively different behavior of the kernels for k odd and k even. It is also related to the chosen numbers of measurement events for different θ : in our

example we have distributed the event numbers so as to minimize Ψ_1 which on the other hand increases the errors of even moments. Even though one could expect that the double homodyning - as a direct phase measurement - would yield generally smaller statistical errors, we find that the statistical error of the first moment Ψ_1 is smaller for the sampled canonical distribution. (The direct measurement means that a single measurement event yields a single value of phase.)

Let us mention that the first moment is connected to very important characteristics of the phase distribution. The mean value of phase $\bar{\varphi}$ can be calculated as $\bar{\varphi} = \arg \Psi_1$; this quantity can correspond, e.g., to a phase shift in an interferometer. Since Ψ_1 is determined more precisely in the balanced homodyning than in the double homodyning, the sampling method enables us to determine $\bar{\varphi}$ with smaller statistical error. From the experimental data we obtain $\bar{\varphi} = 0.5994 \pm 0.0011$ for the sampling method, whereas from the integrated Q function we obtain $\bar{\varphi} = 0.5990 \pm 0.0016$. (Note that for both distributions the correct value is $\bar{\varphi} = \varphi_0 = 0.6$.) As can be seen, the error of determination of the mean phase by means of homodyne sampling is about 70% of the error in the double homodyning. The moment Ψ_1 is also related to various phase uncertainties, which describe the "width" of the phase probability distribution. A phase uncertainty $\Delta \varphi$ can be defined as $\Delta \varphi = \arccos|\Psi_1|$, which is related to the Bandilla-Paul phase dispersion σ_{BP}^2 as $\sigma_{BP} = \sin \Delta \varphi$ and to the Holevo phase dispersion σ_H^2 as $\sigma_H = \tan \Delta \varphi$ [9]. (An advantage of the uncertainty $\Delta \varphi$ is that it enables us to measure the phase width in the same units as the phase itself - in radians, degrees, etc.) In this way we obtain $\Delta \varphi = 0.065$ for the canonical phase distribution and $\Delta \varphi = 0.125$ for the integrated Q function.

4 Discussion and conclusion

The presented method shows a very straightforward way for obtaining the exponential moments of the canonical phase from the data of homodyne detection. Direct sampling enables us to reconstruct the moments Ψ_k in real time as the experiment runs, together with the estimation of the statistical error [8]. In this way the theoretically profound concept of canonical phase can be connected with data obtained from present experiments.

The moments Ψ_k contain the same information as the probability distribution $p(\varphi)$. Therefore they can be used for reconstruction of the original function $p(\varphi)$. However, even the lowest moments give us an interesting information about the phase properties, e.g., the first moment Ψ_1 is directly related to the mean value of phase and to the phase uncertainty.

The integration kernels are well-behaved functions which rapidly approach their asymptotics given either as step-functions (for odd moments) or logarithmic functions (for even moments). As shown in [8], these functions can serve as kernels for sampling of the phase moments in classical physics. Therefore, we have found a unified approach which connects the measurement of the canonical phase with its classical counterpart.

It has been shown that the accuracy of the sampled moments of the canonical phase is comparable with that of the directly measured radially integrated Q function. Moreover, when the total number of measurement events is the same, the sampling method can yield the mean value of phase more precisely than the measurement of the Q function. Also this aspect can make the presented method very attractive for experimental applications.

Acknowledgments

This work was supported by the Deutsche Forschungsgemeinschaft. We are grateful to G.M. D'Ariano, Z. Hradil, and V. Peřinová for stimulating discussions.

* Permanent address: Palacký University, Faculty of Natural Sciences, Svobody 26, 77146 Olomouc, Czech Republic

References

- [1] F. London, Z. Phys. 40, 193 (1927).
- [2] L. Susskind and J. Glogower, Physics 1, 49 (1964); P. Carruthers and M.M. Nieto, Phys. Rev. Lett. 14, 387 (1965), Rev. Mod. Phys. 40, 411 (1968).
- [3] J. W. Noh, A. Fougères, and L. Mandel, Phys. Rev. Lett. 67, 1426 (1991); Phys. Rev. A 45, 424 (1992); ibid 46, 2840 (1992).
- [4] N.G. Walker and J.E. Caroll, Opt. Quant. Electron. 18, 355 (1986); N.G. Walker, J. Mod. Opt. 34, 15 (1987); M. Freyberger, K. Vogel, and W. Schleich, Phys. Lett. A 176, 41 (1993); U. Leonhardt and H. Paul, Phys. Rev. A 48, 4598 (1993).
- [5] U. Leonhardt, J.A. Vaccaro, B. Böhmer, and H. Paul, Phys. Rev. A **51**, 84 (1995).
- [6] G.M. D'Ariano, C. Macchiavello, and M.G.A. Paris, Phys. Rev. A 50, 4298 (1994); U. Leonhardt, H. Paul, and G.M. D'Ariano, Phys. Rev. A52, 4899 (1995); M. Munroe, D. Boggavarapu, M.E. Anderson, and M.G. Raymer, Phys. Rev. A 52, R924 (1995); U. Leonhardt, M. Munroe, T. Kiss, Th. Richter and M.G. Raymer, Opt. Commun. 127, 144 (1996); Th. Richter, Phys. Lett. A 211, 327 (1996);
- [7] M. Dakna, L. Knöll and D.-G. Welsch, Proceedings of the 4th Central-European Workshop on Quantum Optics (Budmerice. 1996), ed. V. Bužek [Act. Phys. Slov. 46, 349 (1996)]; Quantum Semiclass. Opt. 9, 331 (1997); Phys. Rev. A 55, 2360 (1997).
- [8] M. Dakna, T. Opatrný and D.-G. Welsch, submitted to Opt. Commun.
- [9] A. Bandilla and H. Paul, Ann. Phys. (Lpz) 23, 323 (1969); A.S. Holevo, Probabilistic and Statistical Aspects of Quantum Theory (North-Holland, Amsterdam, 1982); T. Opatrný, J. Phys. A 27, 7201 (1994); ibid 28, 6961 (1995).